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**1 Board level reliability testing of  $\mu$ BGA<sup>(R)</sup> packaging with lead-free solder attachment**
*Solberg, V.;*

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**2 A transparent online memory test for simultaneous detection of functional faults and soft errors in memories**
*Thaller, K.; Steininger, A.;*

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Pages:413 - 422

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**4 March U: a test for unlinked memory faults**
*van de Goer, A.J.; Gaydadjiev, G.N.;*

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*van de Goor, A.J.; Gaydadjiev, G.N.; Mikitjuk, V.G.; Yarmolik, V.N.;*  
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*Karimi, F.; Irrinki, S.; Crosbuy, T.; Lombardi, F.;*  
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*Songxin Qi; Quanrang Yang;*  
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